


<b>Search Notes</b>  	<b>Application/Control No.</b>  10533062	<b>Applicant(s)/Patent Under Reexamination</b>  TANIMOTO ET AL.
	<b>Examiner</b>  Sandoval, Patrick	<b>Art Unit</b>  2825

SEARCHED			
Class	Subclass	Date	Examiner
716	1,2	9/27/2007	PS
716	3	8/15/2008	PS

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	9/27/2007	PS
East Search	8/15/2008	PS
Review previously applied prior art references Bowen '301, Panchul '876 and Hines '682	2/13/2008	PS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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